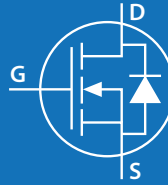


## EPC2040 – Enhancement Mode Power Transistor

 $V_{DS}$ , 15 V $R_{DS(on)}$ , 30 m $\Omega$  $I_D$ , 3.4 A

Revised April 23, 2021

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions:  
Ask a GaN  
Expert



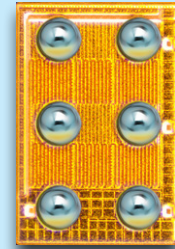
Maximum Ratings			
PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	15	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	18	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 220^\circ\text{C/W}$ )	3.4	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$ )	28	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	5.7	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	39	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	97	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 300 \mu\text{A}$	15			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 12 \text{ V}$		10	250	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.1	1.2	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		10	250	$\mu\text{A}$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 1.5 \text{ A}$		24	30	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage <sup>#</sup>	$V_{GS} = 0 \text{ V}$ , $I_S = 0.5 \text{ A}$		2.2		V

<sup>#</sup> Defined by design. Not subject to production test.  
All measurements were done with substrate connected to source.



Die size: 0.85 x 1.2 mm

EPC2040 eGaN® FETs are supplied only in passivated die form with solder bumps.

**Applications**

- High speed DC-DC conversion
- Lidar/pulsed power applications
- Lidar for augmented reality applications

**Benefits**

- Ultra high efficiency
- Ultra low  $R_{DS(on)}$
- Ultra low  $Q_G$
- Ultra small footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://l.ead.me/EPC2040>

Dynamic Characteristics# (T<sub>J</sub> = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 6 V		86	105	pF
C <sub>RSS</sub>	Reverse Transfer Capacitance			20		
C <sub>OSS</sub>	Output Capacitance			67	100	
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 0 to 6 V		106		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)			87		
R <sub>G</sub>	Gate Resistance			0.5		Ω
Q <sub>G</sub>	Total Gate Charge	V <sub>GS</sub> = 5 V, V <sub>DS</sub> = 6 V, I <sub>D</sub> = 1.5 A		745	925	pC
Q <sub>GS</sub>	Gate-to-Source Charge	V <sub>DS</sub> = 6 V, I <sub>D</sub> = 1.5 A		230		
Q <sub>GD</sub>	Gate-to-Drain Charge			140		
Q <sub>G(TH)</sub>	Gate Charge at Threshold			165		
Q <sub>OSS</sub>	Output Charge	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 6 V		420	630	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

# Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 2: C<sub>OSS(ER)</sub> is a fixed capacitance that gives the same stored energy as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 40% BV<sub>DSS</sub>.

Note 3: C<sub>OSS(TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 40% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C

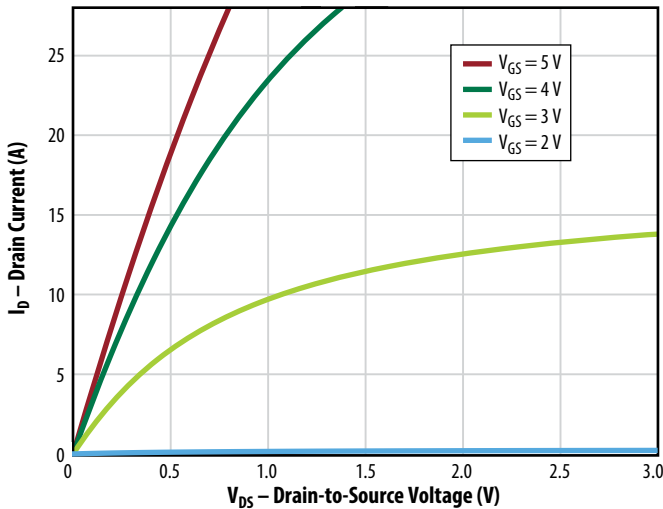


Figure 2: Typical Transfer Characteristics

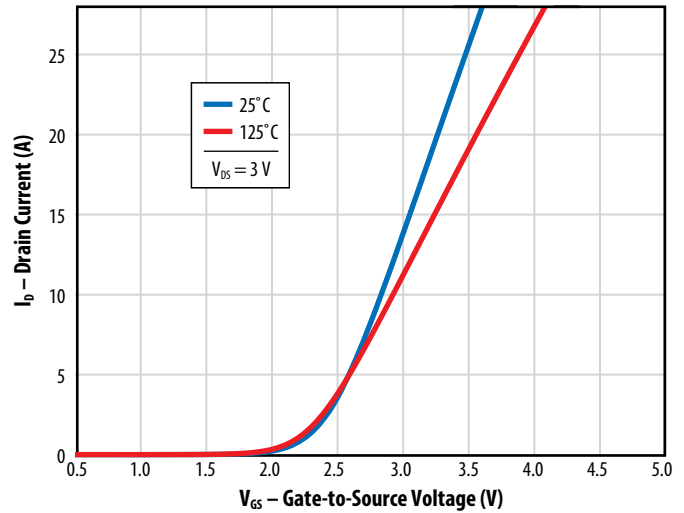


Figure 3: Typical R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Drain Currents

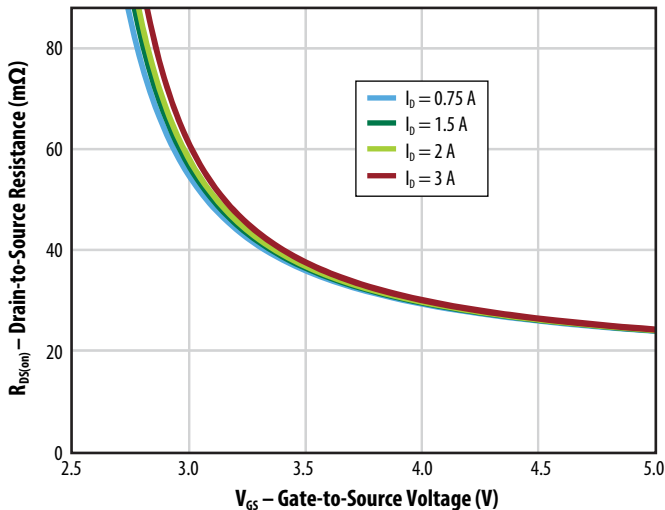


Figure 4: Typical R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

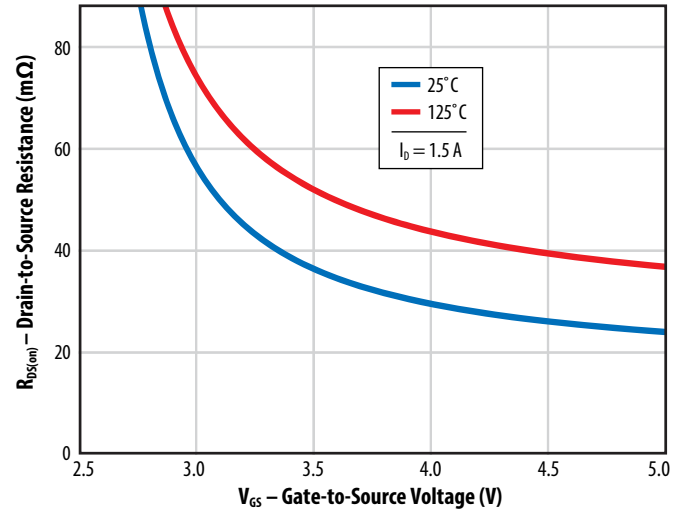


Figure 5a: Typical Capacitance (Linear Scale)

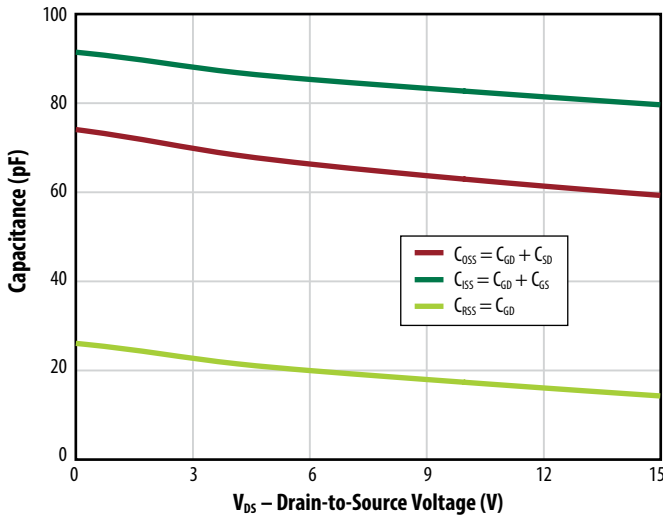


Figure 5b: Typical Capacitance (Log Scale)

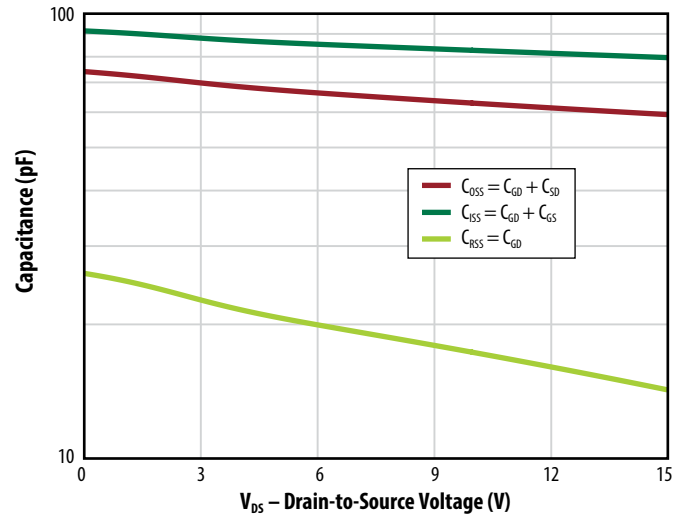


Figure 6: Typical Gate Charge

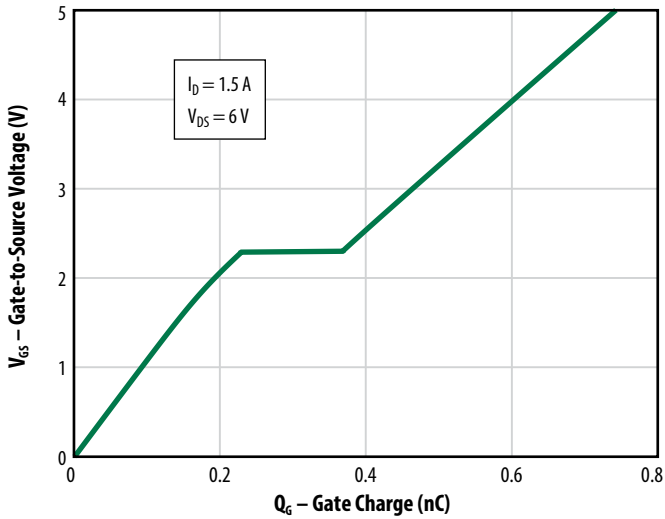
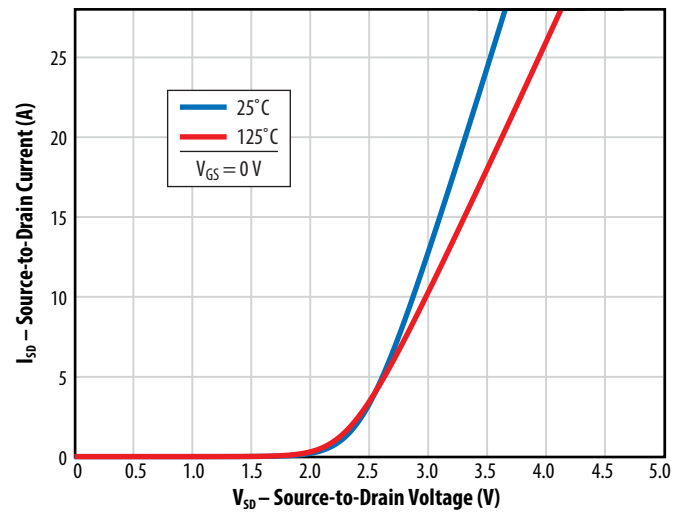


Figure 7: Typical Reverse Drain-Source Characteristics



Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0V for OFF.

Figure 8: Typical Normalized On-State Resistance vs. Temp.

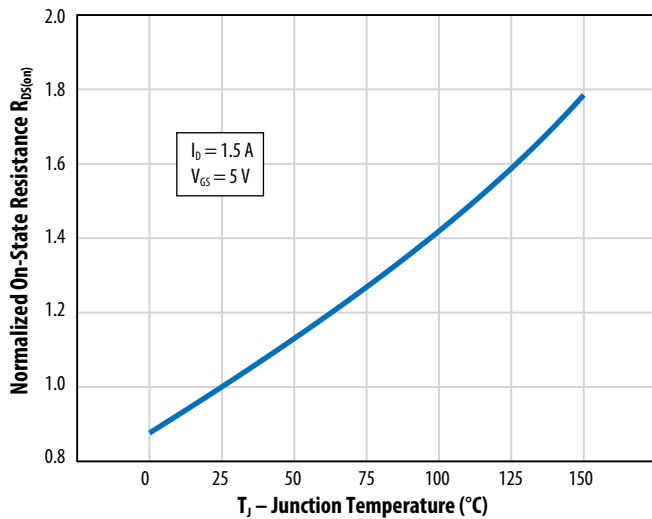


Figure 9: Typical Normalized Threshold Voltage vs. Temp.

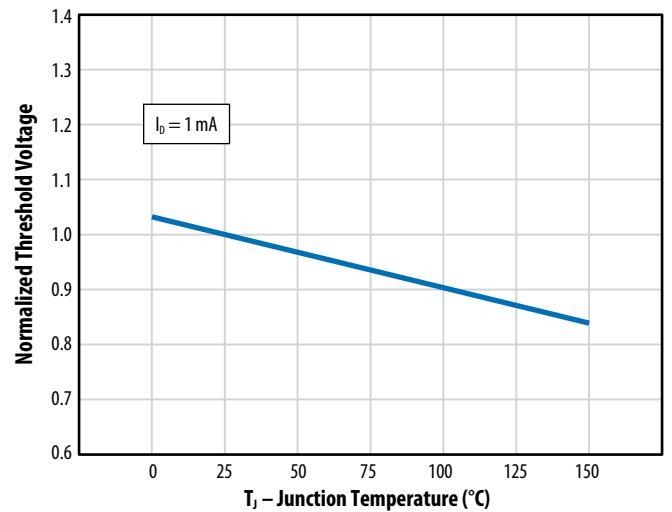


Figure 10: Safe Operating Area

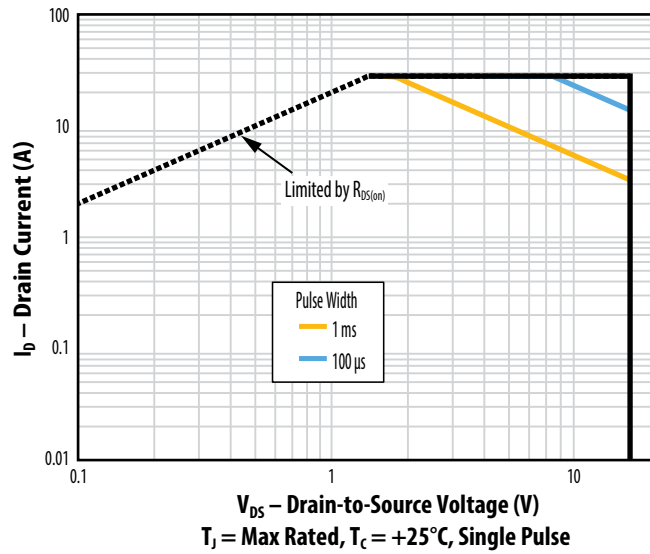
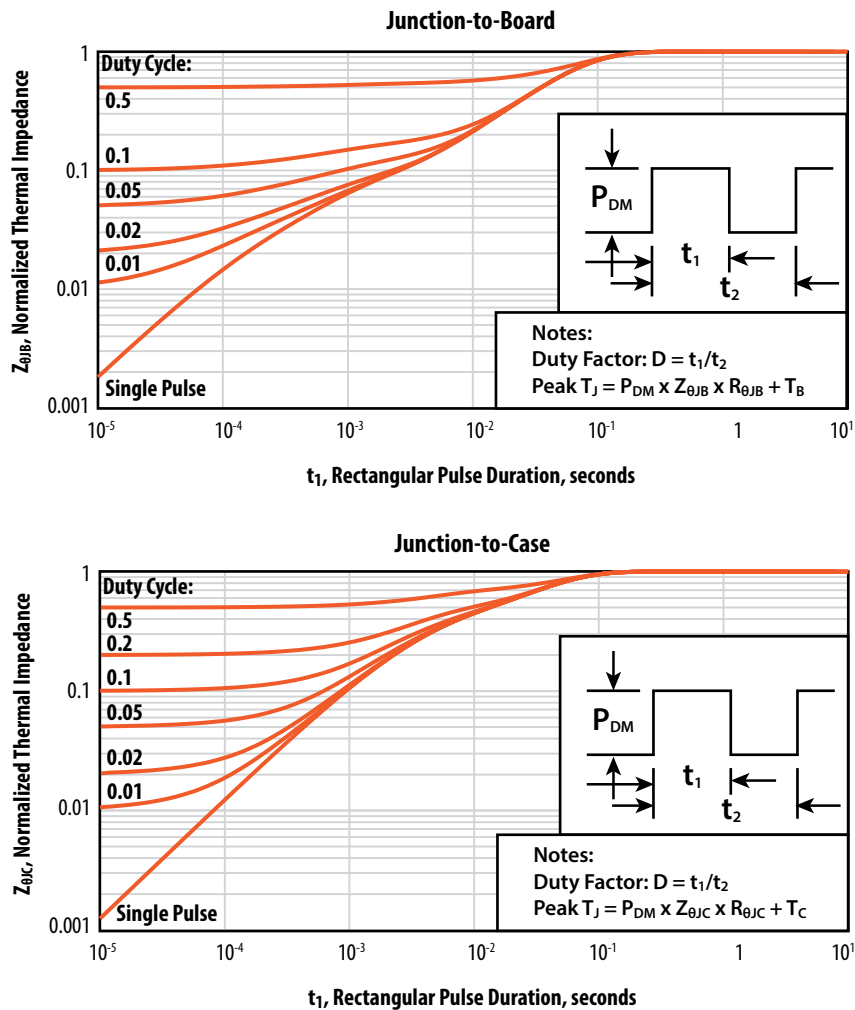
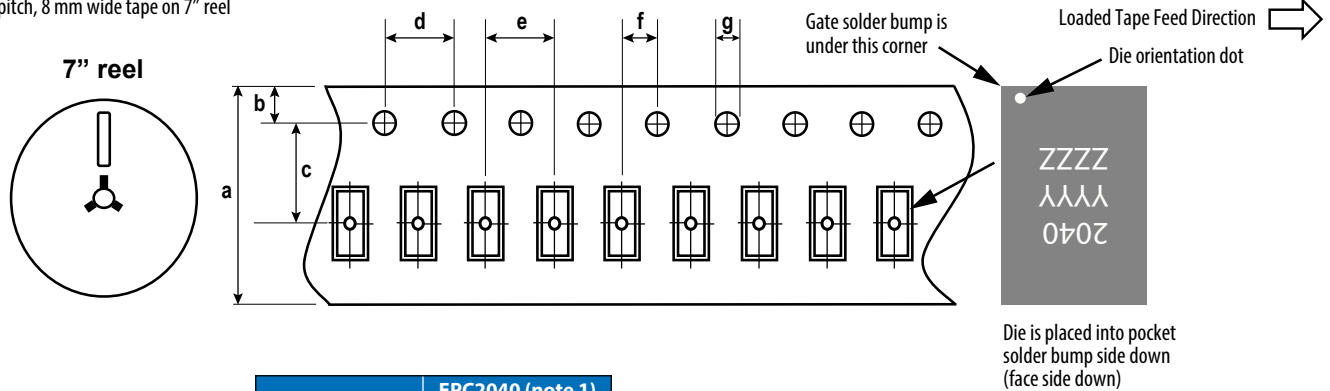


Figure 11: Typical Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

4 mm pitch, 8 mm wide tape on 7" reel

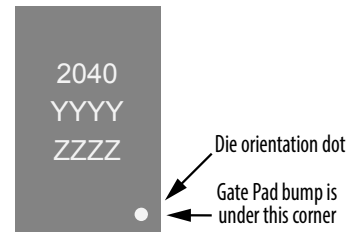


Dimension (mm)	EPC2040 (note 1)		
	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (note 2)	2.00	1.95	2.05
g	1.5	1.5	1.6

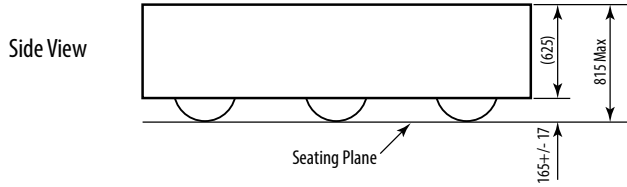
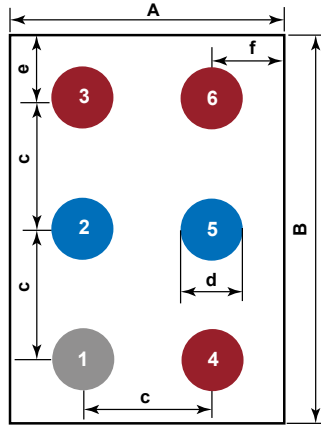
Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.  
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

**DIE MARKINGS**

Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking line 3
EPC2040	2040	YYYY	ZZZZ



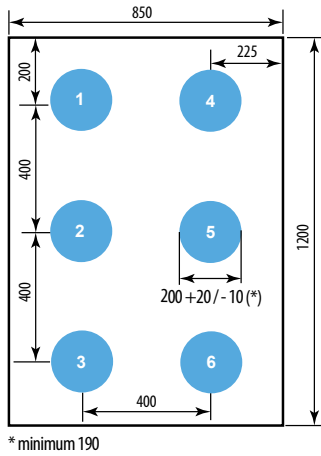
**DIE OUTLINE**  
Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	820	850	880
B	1170	1200	1230
c		400	
d	187	208	229
e	185	200	215
f	210	225	240

Pad 1 is Gate;  
 Pads 2, 5 are Drain;  
 Pads 3, 4, 6 are Source

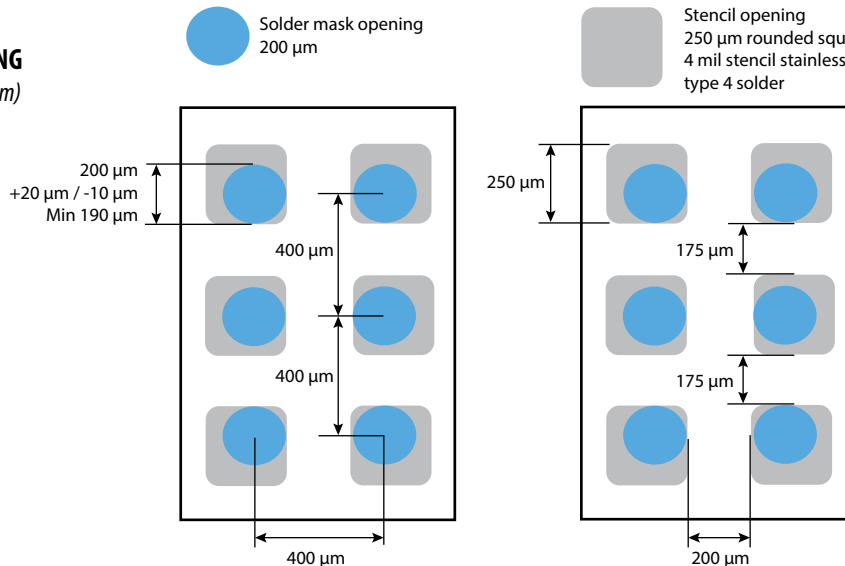
**RECOMMENDED LAND PATTERN**  
(measurements in  $\mu\text{m}$ )



The land pattern is solder mask defined.

Pad 1 is Gate;  
 Pads 2, 5 are Drain;  
 Pads 3, 4, 6 are Source

**RECOMMENDED STENCIL DRAWING**  
(measurements in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at <https://epc-co.com/epc/design-support>

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